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CCS L56

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 21345-2018

Low temperature low noise amplifier test method

低温低噪声放大器测试方法

(English Translation)

Issued by: Ministry of Industry and Information Technology

Preview: page 1 of 3 shown, 8 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21345-2018

Table of Contents

[Preview only]
1 Scope
2 Normative References
2.1 Terms
3 Terms and Definitions
4 Overview
4.1 General requirements
5 Technical Requirements
6 Calibration conditions
6.1 Environmental conditions
6.2 Measurement standards and other equipment
7 Calibration items and calibration methods
7.1 Calibration Items
7.2 Calibration method
8 Expression of calibration results
9 Recalibration interval

1 Foreword

SJ 21345-2018 is issued by Ministry of Industry and Information Technology.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 8 pages in English translation.

2 Scope Preview

SJ 21345-2018 is filed under Chinese Standard Classification L56, in the field of electronic components and information technology.

This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

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https://chinastandards.org/standards/sj-21345-2018

3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 8 pages (approximate)

Chinese original: about 12,115 characters

4 Related standards

Standards on related subjects:

SJ/T 11890-2023 - Design requirement of energy conservation for LED displays

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

SJ 21635-2021 - Semiconductor integrated circuits-Asynchronous dual-port static random access memory (SRAM) test method

SJ 21634-2021 - Semiconductor integrated circuits - Multi-node low-voltage differential signaling (M-LVDS) test methods

SJ 21619-2021 - DC input passive EMI filter test method

5 Classification and status

Chinese Standard Classification (CCS): L 56

Prefix SJ: mandatory standard.

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